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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/676,306	SPEIGLE ET AL.	
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167 _,	3/29/2007	YG		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR) - See search history printout	3/29/2007	YG		
IEEE Xplore	3/29/2007	YG		